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•	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/622,073	HAHN ET AL.
	Examiner	Art Unit
	M. Lee	2622

SEARCHED			
Class	Subclass	Date	Examiner
348	458	3/16/2006	ML
	448	7/21/2006	ML
	449		
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382	299		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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	ce search printout	7/21/2006	ML

SEAR (INCLUDING SI	CH NOT	ES STRATEGY)
		DATE	EXMR
EAST		3/16/2006	ML
Updated		7/21/2006	ML